

Docket No.: 247185US2SRD

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION: Hideo TSUCHIYA, et al.

SERIAL NO.: 10/743,830

GAU: 2886

FILED: December 24, 2003

EXAMINER: NGUYEN, SANG H.

FOR: PATTERN INSPECTING METHOD AND PATTERN INSPECTING APPARATUS

**LETTER SUBMITTING REPLACEMENT DRAWING SHEET(S)**

COMMISSIONER FOR PATENTS

Alexandria, VA 22313

SIR:

Responsive to the below indicated communication, the following drawing sheets are submitted herewith:

☒ 1 Replacement Drawing Sheets ☐ \_\_\_\_\_ New Drawing Sheets

☒ Official Action dated July 3, 2007

☐ Notice of Allowance/Issue Fee dated \_\_\_\_\_

☐ Other dated \_\_\_\_\_

The changes and/or modifications made include the following:

Figure 3 has been amended to overcome the objection in the above mentioned Official Action.

Respectfully Submitted,


OBLON, SPIVAK, McCLELLAND,  
MAIER & NEUSTADT, P.C.

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